

Simao, A., Petrenko, A. *Incremental Test Generation Guided by Fault Coverage*. Montréal, CRIM, 2009. 29 p. [CRIM-09/03-01]

Abstract

We consider a classical problem of complete test generation for deterministic FSMs in a more general setting. The first generalization is that the number of states in implementation FSMs can even be smaller than that of the specification FSM. This generalization provides more options to the test designer: when traditional methods trigger test explosion for large specification machines, tests with a lower, but yet guaranteed, fault coverage can still be generated. The second generalization is that tests can be generated starting with a user-defined test suite, by incrementally extending it until the desired fault coverage is achieved. To solve the generalized test derivation problem, we formulate sufficient conditions for test suite completeness weaker than the existing ones and use them to elaborate an algorithm which can be used both for extending user-defined test suites to achieve the desired fault coverage and for test generation.